

## ABSTRACT OF THE DISCLOSURE

The present invention is a sample-stage for a scanning electron microscope. The sample-stage has a base and a horizontal support member, where there is an aperture in the horizontal support member. A vertical support member abuts the base on one end and the horizontal support member on the other end so that the vertical support member is under, and at an angle to, the aperture in the horizontal support member. A collimator, having an aperture in alignment with the aperture in the horizontal support member, abuts the top of the horizontal support member. A first reflector abuts the surface of the vertical support member under the aperture in the horizontal support . A second reflector abuts a portion of the top surface of the base that is not covered by the vertical support member.